El-Aayah

أعوذ بالله السميع العليم من الشيطان الرجيم بسم الله الرحمن الرحيم ٥

إِنَّ فِي خَلْقِ السَّمَاوَاتِ وَالأَرْضِ وَاخْتِلافِ اللَّيْ لِ وَالنَّهَارِ لَآَيَاتٍ لَّأُولِي الأَلْبَابِ (190) الَّذِينَ يَـذْكُرُونَ اللَّـهَ قِبَامًا وَقُعُـودًا وَعَلَـى جُنُـوبِهِمْ وَيَتَفَكُّرُونَ فِي خَلْقِ السَّمَاوَاتِ وَالأَرْضِ رَبَّنَا مَا خَلَقْتَ هَذَا بَاطِلاً شُبْحَانَكَ فَقِنَا عَـذَابَ النَّارِ ﴿ مَا تَحَلَقْتَ هَذَا بَاطِلاً شُبْحَانَكَ فَقِنَا عَـذَابَ النَّارِ إِلِظَّالِمِينَ مِـنْ أَنصَارِ رَبَّبَنَا إِنَّنَا سَـمِعْنَا مُنَادِيًا يُنَاذِي لِلِيمَانِ أَنْ آمِنُواً بِرَبِّكُمْ فَآمَنَّا وَتَوَقَّنَا مَا يُنَاذِي لِلايمَانِ أَنْ آمِنُواً بِرَبِّكُمْ فَآمَنَّا وَتَوَقَّنَا مَعَ الظَّارِي (193) رَبَّنَا وَلَيْنَا وَآتِنَا مَا وَعَـدَنَّا عَلَى رُسُلِكَ وَلاَ تُخْزِنَا يَوْمَ الْقِيَامَةِ إِنَّكَ لَا وَعَـدَنَّا عَلَى رُسَلِكَ مَوَلاَ تُخْزِنَا يَوْمَ الْقِيَامَةِ إِنَّا مَا وَعَـدَنَا عَلَى رُسُلِكَ مَوَلاَ تُخْزِنَا يَوْمَ الْقِيَامَةِ إِنَّكَ لَا وَعَدَيَّا عَلَى رُسُلِكَ

صدق الله العظيم

سورة آل عمران, الآيات 194-190

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Abstract

This study covers two case studies of optimizing surface modification in polymethyl methacrylate to be used as diffraction grating as well as improving efficiency in Silicon photovoltaic cell.

The first aim of this work is to obtain a textured surface in Poly methylmethacrylate (PMMA), and in Silicon photovoltaic cell by means of laser direct writing machine. The second aim is the characterization of the induced surface texturing by means of Scanning electron microscopy (SEM), Raman mapping, Diffraction patterns achievement and Silicon photovoltaic's Spectral Response Measurement.

In this study, a laser direct writing technique has been utilized to produce photo-thermal and optical density changes in polymethyl methacrylate surface by means of IR continuous laser and to produce micro / nano surface texture in Silicon photovoltaic cell by means of UV femtosecond laser at 180 fs, 400 nm, at 1 kHz repetition rate.

The experimental evidence of the effect of femtosecond laser pulses on the spectral response of a Silicon photovoltaic cell is demonstrated and investigated. The response of this device covered the visible to near infrared spectral region.

It was found that the usage of IR laser radiation (810 nm) with 0.3 Watt power was sufficient to cause significant surface damage on polymethyl methacrylate PMMA.

SEM results showed formation of almost flat cracks (fissures) in PMMA sample, Raman mapping showed variations in the intensity of background scattering light in the structure of PMMA sample, no shift in Raman peaks and no new peaks appeared after irradiation process. Optical density changes caused by thermal and stress effects and plastic deformation products rather than photochemical changes may be thereby also related to refractive index modification.

Laser texturing makes it possible to increase absorption of the incident solar radiation, this texturing technique produce micro/nano surface textures in Silicon photovoltaic cell by means of UV femtosecond laser pulses. The responsivity of the photovoltaic cell was increased up to 0.25A/W.

In conclusions, the results summarized above showed that laser direct writing technique is fast and easy to produce PMMA diffraction grating as well as high quality Silicon photovoltaic cells.

This mechanism is strongly dependent on the optical properties of the material and is recommended to be studied experimentally and theoretically in the future.

المستخلص

يغطي هذا العمل دراسة حالتين الأولى لتحسين التعديلات السطحية لعينة من البولي ميثابل ميتاكريلات لغرض استخدامه كمحزوز حيود ولأخرى عن تحسين الكفاءة في الخلية الضوئية السليكونية.

الهف الأول من هذا العمل هو الحصول على سطح معل بالليزر في كل من البولي ميثابل ميتاكريلات (PMMA))، والخلية الضوئية السيليكونية عن طريق منظومة (الكتابة) المباشرة بالليزر. والهف الثاني هو فص التركيب السطحي الناتج بولسطة المجهر الإلكتروني الملسح (SEM), مطيافية رامان, الحصول على نمط الحيود وقيلسات الإستجابة الطيفية للخلية الضوئية السليكونية.

في هذه الدراسة، تم استخدام منظومة (الكتابة) المباشرة بالليزر للحصول على تغيرات حرارية ضوئية وتغيرات في الكثافة البصرية في سطح البولي ميثايل ميتاكريلات بليزر الثنائي بنمط مستمر وكذلك للحصول على زخرفة سطحية مايكرونية/ نانوية على الخلية الضوئية السليكونية بليزر نضي بزمن نضة 180 فيمتوثانية ، وطول موجي 400 نانومتر و بمعدل تكرار 1 كيلو هرتز.

أرضحت النتائج التجريبية تأثير نبضلت الليزر بالفيمتو ثانية على الإستجابة الطيفية للخلية الضوئية السيليكونية حيث أن استجابة هذه الخلية تغطي المنطقة الطيفية المرئية والأشعة تحت الحمراء القريية.

وجد أن استخدام أشعة ليزر الثنائي تحت الحمراء (810 نانومتر) بقدرة 0.3 واط ، كان كافياً لعمل التغييرات على سطح البوليمر PMMA.

أظهرت نتائج جهاز المجهر الإلكتروني الملسح تكوّن بض التصدعات في عينة البوليمر. وأظهرت نتائج جهاز رامل وجود اختلافات في شدة تشتت الخلفية الضوئية من تركيب عينة البوليمر PMMA ولم يتغيير موقع أي قمة في طيف رامل ولم تظهر أي قمم جديدة بعد التشعيع. وجد أن هناك تغيرات في الوزن الجزيئي وفي الكثافة الضوئية ناجمة عن التأثيرات الحرارية والإجهاد، وتشوه بلاستيكي كلها تغيرات نتجت بدلاً من التغييرات الكيميائية الضوئية وهي تتعلق بتغيير معلمل الانكسار.

حفر السطح بالليزر جعلت من الممكن زيادة لمتصل الإشعة الشمسية الساقطة، تُنتج هذه التقنية تركيب نانو المايكروني في سطح الخلية الضوئية السيليكونية بلستحدام التشعيع بليزر الأشعة فوق البنفسجية النبضي بالفيمتو ثانية. وجد أن استجابية هذه الخلية الضوئية تصل الى A / W 0.25.

لن النتائج أعلاه تبين أن تقنية النقر بالليزرعبارة عن تقنية سهلة وسريعة للحصل على مجزوز حيود بوليمري وكذلك للحصول على خلايا ضوئية عالية الجودة.

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List of Abbreviations

3-D	Three Dimensions
AFM	Atomic-force microscopy
APS	Air Plasma Sprayed
BBO	Beta Barium Borate
CARS	Coherent Anti-Stokes Raman
CCD	Charge-Coupled Devices
CW	Continuous-wave
DSC	3 Differential scanning calorimetry
$E_{ m bg}$	band gap
EDS	Energy-dispersive X-ray Spectroscopy
E_{F}	Fermi energy
fs	Femtosecond
HAZ	heat affected zone
IR	infra-red
LDPE	low density polyethylene

LDW Laser Direct Writing

LDW-laser direct write subtraction

- LDW+ laser direct-write addition
- LDWM laser direct-write modification
- LIBWE laser-induced backside wet etching
- LIFT laser induced forward transfer
- LiNbO₃ Lithium Niobate
- LO longitudinal-optical
- ND natural density
- Nd:YAG neodymium-doped yttrium aluminium garnet; Nd:Y₃Al₅O₁₂
- NIR near infrared
- PDA Photodiode Arrays
- PDMS poly dimethyl siloxane
- PDMS Poly dimethylsiloxane
- PMA poly(methyl acrylate)
- PMMA poly(methyl methacrylate)
- PMT Photomultiplier Tubes
- POF polymer optical fibre
- ps picosecond
- PS polystyrene
- PVA poly vinylalcohol
- RR Resonance Raman
- SEM scanning Electron Microscopy
- SERRS Surface-Enhanced Raman Resonance Spectroscopy
- SERS Surface-Enhanced Raman Spectroscopy
- SFF solid free-form fabrication

- SHG Second-harmonic-generation
- SLS selective laser sintering
- *T*_e electron temperature

Ti: Sapphire titanium–sapphire

$T_{ m m}$	equilibrium melting point
UV	ultraviolet
Vis	visible
WDM	wavelength-division multiplexing
XRD	X-ray diffraction